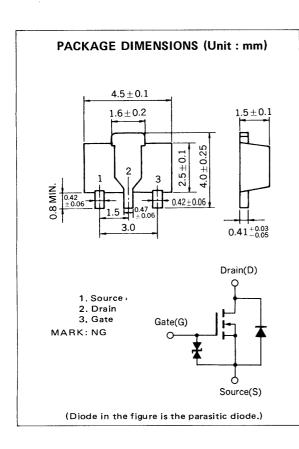


MOS FIELD EFFECT TRANSISTOR 2SK1588

N-CHANNEL MOS FET FOR SWITCHING



The 2SK1588 is an N-channel vertical type MOS FET which can be driven by 2.5 V power supply.

As the MOS FET is driven by low voltage and does not require consideration of driving current, it is suitable for appliances including VCR cameras and headphone stereos which need power saving.

FEATURES

- Directly driven by ICs having a 3 V power supply.
- Has low on-state resistance

 $R_{DS(on)1}$ = 0.5 Ω MAX. @ V_{GS} = 2.5 V, I_{D} = 1.0 A $R_{DS(on)2}$ = 0.3 Ω MAX. @ V_{GS} = 4.0 V, I_{D} = 1.5 A

QUALITY GRADE

Standard

Please refer to "Quality grade on NEC Semiconductor Devices" (Document number IEI-1209) published by NEC Corporation to know the specification of quality grade on the devices and its recommended applications.

ABSOLUTE MAXIMUM RATINGS (Ta = 25 $^{\circ}$ C)

PARAMETER	SYMBOL	RATINGS	UNIT	TEST CONDITIONS
Drain to Source Voltage	V _{DSS}	16	V	V _{GS} = 0
Gate to Source Voltage	V _{GSS}	±16	V	V _{DS} = 0
Drain Current	ID(DC)	±3.0	А	
Drain Current	I _{D(pulse)}	±6.0	А	PW ≤ 10 ms, Duty Cycle ≤ 50 %
Total Power Dissipation	PT	2.0	w	When using ceramic board of 16 cm ² x 0.7 mm
Channel Temperature	T _{ch}	150	°C	
Operating Temperature	T _{opt}	-55 to +80	°C	
Storage Temperature	T _{stg}	-55 to +150	°C	

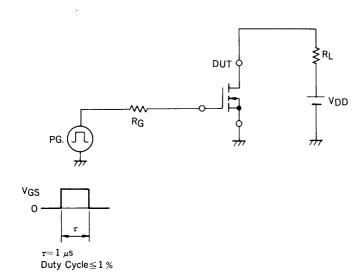
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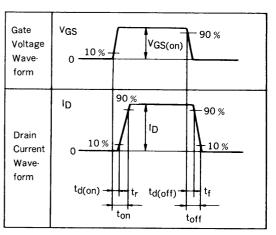


ELECTRICAL CHARACTERISTICS (T_a = 25 °C)

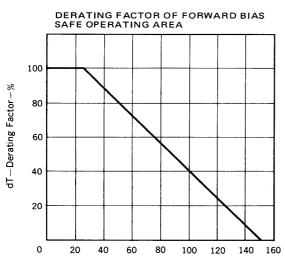
PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT	TEST CONDITIONS
Drain Cut-off Current	IDSS			1.0	μА	V _{DS} = 16 V, V _{GS} = 0
Gate Leakage Current	¹ GSS			±5.0	μА	V _{GS} = ±16 V, V _{DS} = 0
Gate Cut-off Voltage	VGS(off)	0.8	1.0	1.6	V	V _{DS} = 5 V, I _D = 1 mA
Forward Transfer Admittance	ly _{fs} !	0.4	3.0		S	V _{DS} = 3 V, I _D = 1.0 A
Drain to Source On-State Resistance	R _{DS(on)1}		0.25	0.5	Ω	V _{GS} = 2.5 V, I _D = 1.0 A
Drain to Source On-State Resistance	RDS(on)2		0.17	0.3	Ω	V _{GS} = 4.0 V, I _D = 1.5 A
Input Capacitance	C _{iss}		240		pF	
Output Capacitance	Coss		250		pF	V _{DS} = 3.0 V, V _{GS} = 0, f = 1 MHz
Feedback Capacitance	C _{rss}		60		pF	
Turn-On Delay Time	^t d(on)		140		ns	
Rise Time	t _r		650		ns	V _{DD} = 3 V, I _D = 1.5 A
Turn-Off Delay Time	^t d(off)		120		ns	$V_{GS(on)} = 3 \text{ V, R}_{G} = 10 \Omega$ $R_{L} = 2 \Omega$
Fall Time	tf		160		ns	

SWITCHING TIME MEASUREMENT CIRCUIT AND CONDITIONS

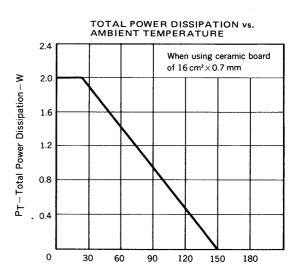




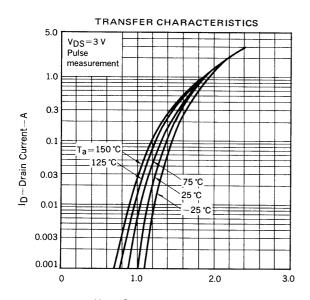
TYPICAL CHARACTERISTICS ($T_a = 25$ °C)

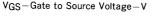


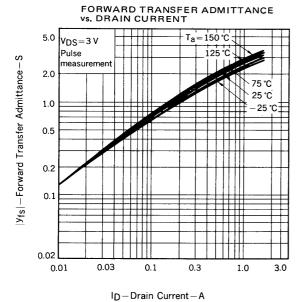


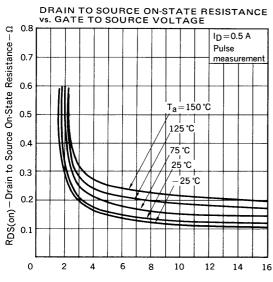


Ta-Ambient Temperature-°C



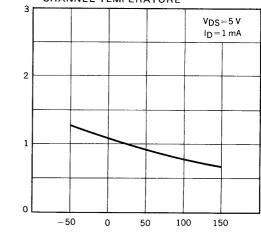






VGS-Gate to Source Voltage-V

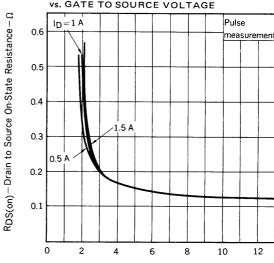
GATE TO SOURCE CUTOFF VOLTAGE vs. CHANNEL TEMPERATURE 3



VGS(off)—GateCut-Off Voltage-V

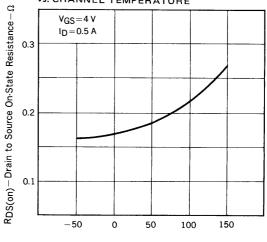
T_{ch}-Channel Temperature-°C

DRAIN TO SOURCE ON-STATE RESISTANCE vs. GATE TO SOURCE VOLTAGE

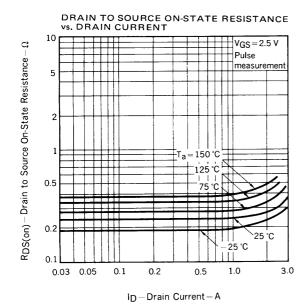


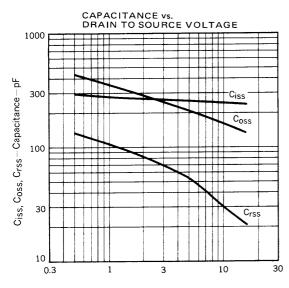
VGS-Gate to Source Voltage-V

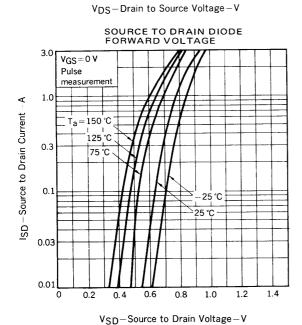
DRAIN TO SOURCE ON-STATE RESISTANCE vs. CHANNEL TEMPERATURE

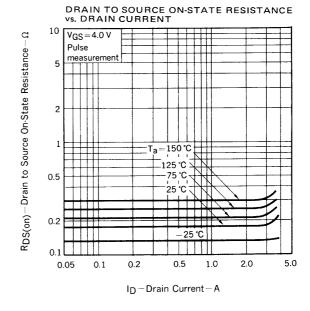


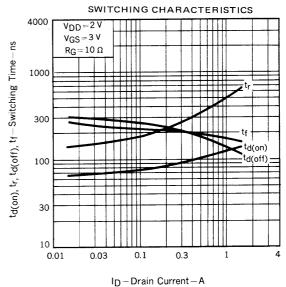
 $\mathsf{T}_{\mathsf{Ch}}\!-\!\mathsf{Channel}\ \mathsf{Temperature}\!-^\circ\!\mathsf{C}$













RECOMMENDED SOLDERING CONDITIONS

Mounting of this product by soldering should be done under the following conditions.

Please consult our representatives about soldering methods and conditions other than these.

SURFACE MOUNT TYPE

For details of the recommended soldering conditions, see the information document "SMT MANUAL" (IEI-1207).

Soldering Method	Soldering Conditions	Symbol for Recommended Conditions
Infrared Reflow	Package peak temp.: 230 °C Soldering time: within 30 sec (above 210 °C) Soldering times: 1, Days limitation: none*	IR30-00
Vapor Phase Soldering	Package peak temp.: 215 °C Soldering time: within 40 sec (above 200 °C) Soldering times: 1, Days limitation: none*	VP15-00
Wave Soldering	Soldering bath temp.: below 260 °C Soldering time: within 10 sec Soldering times: 1, Days limitation: none*	WS60-00

^{*:} Stored days under storage conditions at 25 °C and below 65 % R.H. after the dry-pack has been opened.

Note 1 Combination of soldering methods should be avoided.

REFERENCE

Document Name	Document No.	
NEC semiconductor device reliability/quality control system.	TEI-1202	
Quality grade on NEC semiconductor devices.	IEI-1209	
Semiconductor device mounting technology manual.	IEI-1207	
Semiconductor device package manual.	IEI-1213	
Guide to quality assurance for semiconductor devices.	MEI-1202	
Semiconductor selection guide.	MF-1134	

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Standard: Computer, Office equipment, Communication equipment, Test and Measurement equipment, Machine tools, Industrial robots, Audio and Visual equipment, Other consumer products, etc.

Special: Automotive and Transportation equipment, Traffic control systems, Antidisaster systems, Anticrime systems, etc.

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